

**Search Notes**

Application/Control No.

10/660,957

Examiner

Ellen C. Tran

Applicant(s)/Patent under  
Reexamination

HAYES ET AL.

Art Unit

2134

**SEARCHED**

Class	Subclass	Date	Examiner
380	249	2/16/2007	ECT
380	247	2/16/2007	ECT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	2/16/2007	ECT
NPL - IEEE XPLORE	2/16/2007	ECT
INVENTOR SEARCH - PALM/eDAN	2/16/2007	ECT
All claims were reviewed for 101 rejections	2/16/2007	ECT